


<b>Search Notes</b>  	<b>Application/Control No.</b>  10690330	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  Feben M Haile	<b>Art Unit</b>  2616

SEARCHED			
Class	Subclass	Date	Examiner
370	392, 395.51, 395.53, 466, 469, 471, 474	3/12/2008	FH
398	45, 58, 63	3/12/2008	FH
710	30	3/12/2008	FH

SEARCH NOTES		
Search Notes	Date	Examiner
mac, frame, ethernet, optical, pon, epon, llid, tag, label, identifier, physical layer, data layer, olt, onu, add, tag, reconfigure, append, affix, annex, flag, field, insert, stack	3/12/2008	FH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner